

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KAWABE ET AL.	
		Examiner David H. Chu	Art Unit 2628	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,185,625 B1	02-2001	Tso et al.	709/247
*	B	US-6,310,601 B1	10-2001	Moore et al.	345/660
*	C	US-2002/0032035 A1	03-2002	Teshima, Toru	455/456
*	D	US-6,356,283 B1	03-2002	Guedalia, Joshua Siegfried	715/760
*	E	US-2002/0069220 A1	06-2002	Tran, Bao Q.	707/503
*	F	US-2002/0091808 A1	07-2002	FUKASAWA et al.	709/223
*	G	US-6,715,003 B1	03-2004	Safai, Mohammad A.	710/33
*	H	US-2005/0116966 A1	06-2005	Graham et al.	345/661
*	I	US-7,032,172 B1	04-2006	Lee et al.	715/526
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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